



# CERTIFICATE OF ACCREDITATION

**The ANSI National Accreditation Board**

Hereby attests that

**Houston Precision Incorporation  
6633 Polk Street  
Houston, TX 77011**

Fulfills the requirements of

**ISO/IEC 17025:2017**

and

**ANSI/NCSL Z540-1-1994 (R2002)**

In the field of

**CALIBRATION**

This certificate is valid only when accompanied by a current scope of accreditation document.  
The current scope of accreditation can be verified at [www.anab.org](http://www.anab.org).

Jason Stine, Vice President

Expiry Date: 28 April 2027

Certificate Number: AC-3202



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.  
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory  
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

**SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017**

**AND**

**ANSI/NCSL Z540-1-1994 (R2002)**

**Houston Precision Incorporation**

6633 Polk Street  
Houston, TX 77011  
Gary Deterling 713-943-1155

**CALIBRATION**

Valid to: **April 28, 2027**

Certificate Number: **AC-3202**

**Length – Dimensional Metrology**

<b>Parameter/Equipment</b>	<b>Range</b>	<b>Expanded Uncertainty of Measurement (+/-)</b>	<b>Reference Standard, Method, and/or Equipment</b>
Calipers <sup>1,2</sup>	Up to 6 in (6 to 80) in	840 μin (740 + 17L) μin	Comparison to Gage Blocks
Height Gages <sup>1,2</sup>	Up to 6 in (6 to 80) in	840 μin (740 + 17L) μin	Comparison to Gage Blocks
Outside Micrometers <sup>1</sup>	Up to 1 in (6 to 80) in	73 μin 860 μin	Comparison to Gage Blocks
Optical Comparators <sup>1,2</sup> X-Y Linearity	Up to 6 in (6 to 30) in	150 μin (87 + 9.4L) μin	Comparison to Glass Grid
Angle	Up to 90°	1.3"	Glass Grid
Magnification	10X, 20X, 30X	0.002 3 in	Magnification Scale
Surface Plates <sup>1,2</sup>			In accordance with ASME B89.3.7 using Electronic Level System
Overall Flatness	Up to 170 inDL	(18 + 1.1DL) μin	
Local Area Flatness (Repeat Readings)	Up to 0.04 in	7 μin	Repeat-O-Meter
MIC-TRAC <sup>1,2</sup>	Up to 12 in (12 to 24) in (24 to 36) in	(44 + 3.8L) μin (39 + 4.2L) μin (91 + 2.1L) μin	Comparison to Renishaw XL-80 Laser Measurement System
Micrometer Standards <sup>2</sup>	Up to 6 in (6 to 24) in (24 to 36) in	930 μin (920 + 1.1L) μin (910 + 1.7L) μin	Comparison to Gagemaker MIC TRAC Measurement System

**Length – Dimensional Metrology**

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Micrometer Standards <sup>2</sup>	(36 to 80) in	$(830 + 3.4L) \mu\text{in}$	Comparison to Gagemaker MIC TRAC Measurement System, Renishaw XL-80 Laser Measurement System

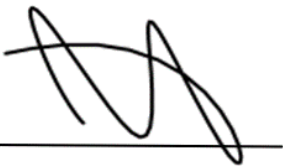
**Thermodynamic**

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Pyrometers <sup>1</sup>	(50 to 700) °C	2.7 °C	Comparison to Presys T1200PIR Blackbody Source (flat plate) $\epsilon = 0.99, \lambda = (8 \text{ to } 14) \mu\text{m}$

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ( $k=2$ ), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
2.  $L$  = length in inches;  $DL$  = diagonal length in inches; " = arc-second.
3. Unless otherwise specified in the far-right hand column, the calibration procedure being utilized by the laboratory was written internally.
4. This scope is formatted as part of a single document including Certificate of Accreditation No. AC-3202.



Jason Stine, Vice President